

54F/74F521 8-Bit Identity Comparator

General Description

The 'F521 is an expandable 8-bit comparator. It compares two words of up to eight bits each and provides a LOW output when the two words match bit for bit. The expansion input $\vec{l}_{A=B}$ also serves as an active LOW enable input.

Features

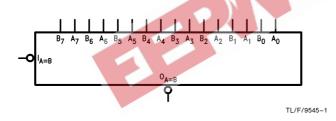
- Compares two 8-bit words in 6.5 ns typ
- Expandable to any word length
- 20-pin package

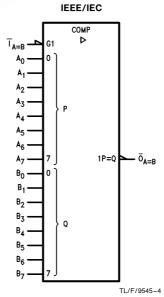
Commercial	Military	Package Number	Package Description		
74F521PC		N20A	20-Lead (0.300" Wide) Molded Dual-In-Line		
	54F521DM (Note 2)	J20A	20-Lead Ceramic Dual-In-Line		
74F521SC (Note 1)		M20B	20-Lead (0.300" Wide) Molded Small Outline, JEDEC		
74F521SJ (Note 1)		M20D	20-Lead (0.300" Wide) Molded Small Outline, EIAJ		
74F521MSA (Note 1)		MSA20	20-Lead Molded Shrink Small Outline, EIAJ type II		

Note 1: Devices also available in 13" reel. Use suffix = SCX, SJX and MSAX.

Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB.

Logic Symbols





TRI-STATE® is a registered trademark of National Semiconductor Corporation.

Unit Loading/Fan Out

		54F/74F			
Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}		
A ₀ -A ₇	Word A Inputs	1.0/1.0	20 μA/ – 0.6 mA		
B ₀ -B ₇	Word B Inputs	1.0/1.0	20 μA/ - 0.6 mA		
Ī _{A=B}	Expansion or Enable Input (Active LOW)	1.0/1.0	20 μA/ -0.6 mA		
$\overline{O}_{A=B}$	Identity Output (Active LOW)	50/33.3	-1 mA/20 mA		

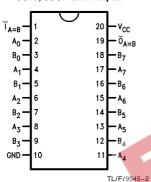
Truth Table

Inj	Output		
$\bar{I}_{A} = B$	A, B	$\overline{O}_{A} = B$	
L	A = B*	L	
L	$A \neq B$	Н	
Н	$A = B^*$	Н	
Н	A eq B	Н	

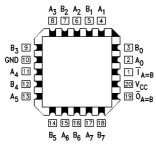
 $\begin{array}{ll} H = \text{HIGH Voltage Level} \\ L = \text{LOW Voltage Level} \\ *A_0 = B_0, \, A_1 = B_1, \, A_2 = B_2, \, \text{etc.} \end{array}$

Connection Diagrams

Pin Assignment for DIP, SOIC, SSOP and Flatpak

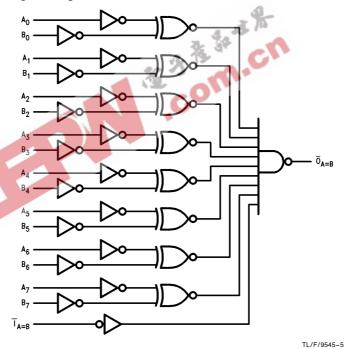


Pin Assignment for LCC



TL/F/9545-3

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to} + 125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to} + 175^{\circ}\mbox{C} \\ \mbox{Plastic} & -55^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \end{array}$

 $\begin{array}{lll} \text{V}_{\text{CC}} \text{ Pin Potential to} & & & \\ \text{Ground Pin} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Voltage (Note 2)} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Current (Note 2)} & -30 \text{ mA to } +5.0 \text{ mA} \end{array}$

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{lll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{TRI-STATE} \bullet \text{Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature

Supply Voltage

 Military
 + 4.5V to + 5.5V

 Commercial
 + 4.5V to + 5.5V

DC Electrical Characteristics

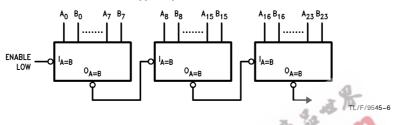
	Parameter -		54F/74F			Units V _{CC}		Conditions	
Symbol			Min Typ Max						
V _{IH}	Input HIGH Voltage		2.0		26	V	400	Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Vol	tage	7		-1.2	V	Min	$I_{\text{IN}} = -18 \text{ mA}$	
V _{OH}	Output HIGH Voltage	54F 10% V _{CC} 74F 10% V _{CC} 74F 5% V _{CC}	2.5 2.5 2.7			V	Min	$I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$	
V _{OL}	Output LOW Voltage	54F 10% V _{CC} 74F 10% V _{CC}			0.5 0.5	٧	Min	$I_{OL} = 20 \text{ mA}$ $I_{OL} = 20 \text{ mA}$	
Ін	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	$V_{IN} = 2.7V$	
I _{BVI}	Input HIGH Curre <mark>nt</mark> Breakdown Test	54F 74F			100 7.0	μΑ	Max	V _{IN} = 7.0V	
ICEX	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$	
V_{ID}	Input Leakage Test	74F	4.75			V	0.0	$I_{\text{ID}} = 1.9 \mu\text{A}$ All Other Pins Grounded	
l _{OD}	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V _{IOD} = 150 mV All Other Pins Grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$	
Ios	Output Short-Circuit Co	urrent	-60		-150	mA	Max	$V_{OUT} = 0V$	
Icch	Power Supply Current	•		21	32	mA	Max	V _O = HIGH	

AC Ele	ectrical	Chara	cteristics

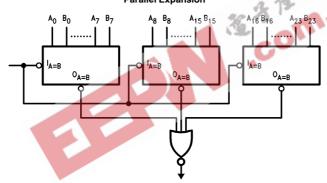
Symbol	Parameter	$74F$ $T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{I} = 50 \text{ pF}$			54F T _A , V _{CC} = Mil C _L = 50 pF		74F T _A , V _{CC} = Com C _L = 50 pF		Units
		Min	Тур	Max	Min	Max	Min	Max]
t _{PLH}	Propagation Delay A_n or B_n to $\overline{O}_{A=B}$	3.0 4.5	7.0 7.0	10.0 10.0	3.0 4.0	14.0 15.0	3.0 4.0	11.0 11.0	ns
t _{PLH}	Propagation Delay $\overline{I}_{A=B}$ to $\overline{O}_{A=B}$	3.0 3.5	5.0 6.5	6.5 9.0	3.0 3.5	8.5 13.5	3.0 3.5	7.5 10.0	ns

Applications

Ripple Expansion



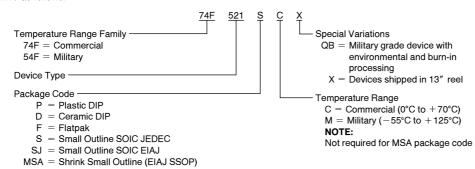
Parallel Expansion

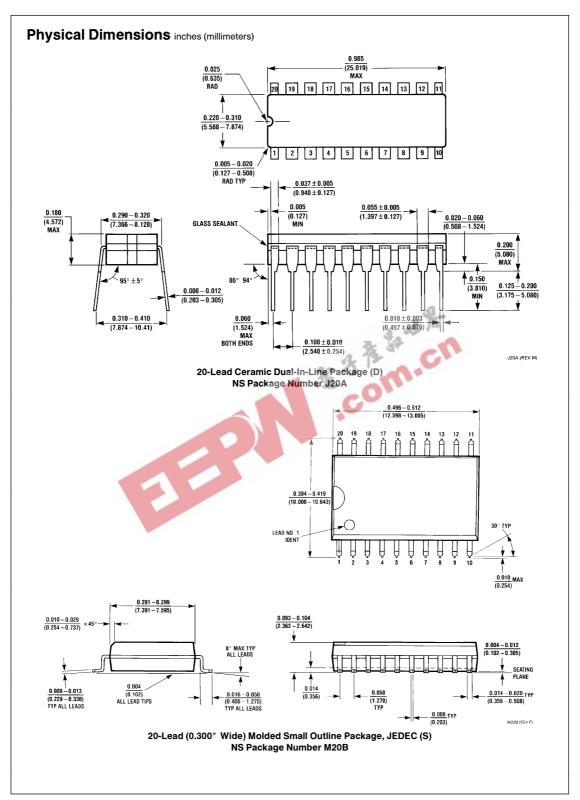


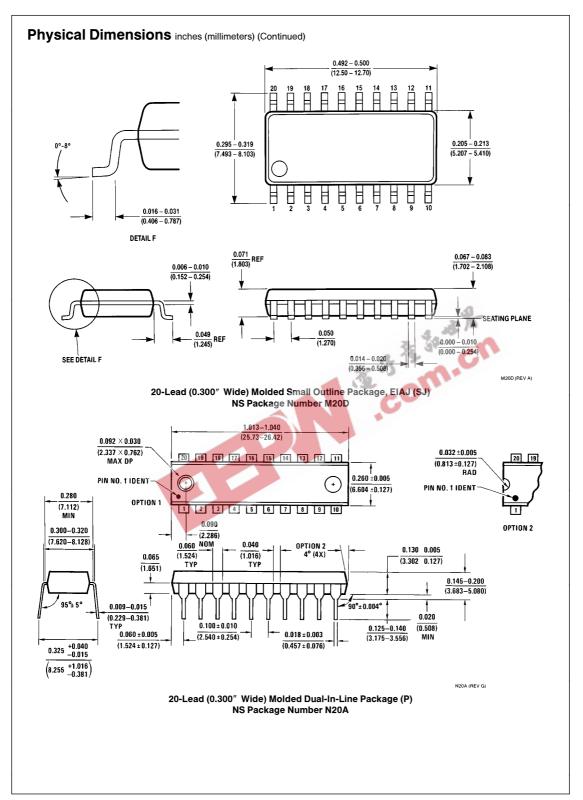
TL/F/9545-7

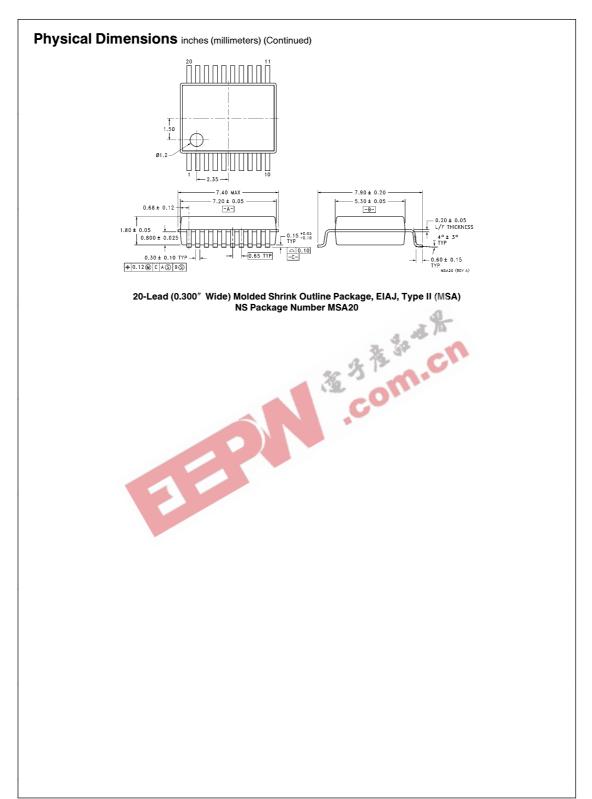
Ordering Information

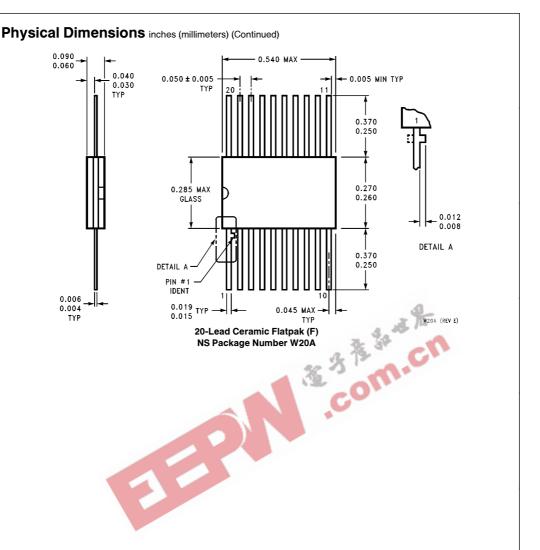
The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:











LIFE SUPPORT POLICY

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



National Semiconductor Corporation 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, CA 95052-8090 Tet: 1(800) 272-9959 TWX: (910) 339-9240

GmbH Livry-Gargan-Str. 10 D-82256 Fürstenfeldbru Germany Tel: (81-41) 35-0 Telex: 527649 Fax: (81-41) 35-1

National Semiconducto

National Semiconductor Japan Ltd. Sumitomo Chemical Engineering Center Bildg. 7F 1-7-1, Nakase, Mihama-Ku Chiba-City, Ciba Prefecture 261 Tel: (043) 299-2300 Fax: (043) 299-2500

National Semiconductor Hong Kong Ltd. 13th Floor, Straight Block, Ocean Centre, 5 Canton Rd. Tsimshatsui, Kowloon J Hong Kong Tel: (852) 2737-1600 Fax: (852) 2736-9960 National Semiconductores Do Brazil Ltda. Rue Deputado Lacorda Franco 120-3A Sao Paulo-SP Brazil 05418-000 Tel: (55-11) 212-5066 Telex: 391-1131931 NSBR BR Fax: (55-11) 212-1181 National Semiconducto (Australia) Pty, Ltd. Building 16 Business Park Drive Monash Business Park Nottinghill, Melbourne Victoria 3168 Australia Tel: (3) 558-9999 Fax: (3) 558-9998